UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/593,141	07/25/2007	Gerald Meinhardt	5367-264PUS	8752
	7590 04/09/200 ΓΑΝΙ, LIEBERMAN &	EXAMINER		
551 FIFTH AV		LINDSAY JR, WALTER LEE		
SUITE 1210 NEW YORK, NY 10176			ART UNIT	PAPER NUMBER
			2812	
			MAIL DATE	DELIVERY MODE
			04/09/2009	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

		Application	No.	Applicant(s)				
Office Action Summary		10/593,141		MEINHARDT ET AL.				
		Examiner		Art Unit				
		Walter L. Lind	•	2812				
The MAILING DATE of th Period for Reply	is communication app	ears on the co	ver sheet with the c	orrespondence ad	ldress			
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).								
Status								
1)☐ Responsive to communic	ation(s) filed on							
2a) This action is FINAL .		–· action is non⋅	final					
/ —	<i>,</i> —			secution as to the	marite ie			
•	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
closed in accordance with	Tine practice ander Z	.x parte Quayi	c, 1999 O.D. 11, 40	0.0.210.				
Disposition of Claims								
4)⊠ Claim(s) <u>16-29</u> is/are per	☑ Claim(s) <u>16-29</u> is/are pending in the application.							
4a) Of the above claim(s)	4a) Of the above claim(s) is/are withdrawn from consideration.							
5) Claim(s) is/are allo	5) Claim(s) is/are allowed.							
6)⊠ Claim(s) <u>16-29</u> is/are reje	S)⊠ Claim(s) <u>16-29</u> is/are rejected.							
7) Claim(s) is/are obj	ected to.							
8) Claim(s) are subje	ct to restriction and/or	r election requ	irement.					
Application Papers								
9)☐ The specification is object	ed to by the Examine	r.						
10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.								
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).								
					FR 1.121(d).			
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.								
Priority under 35 U.S.C. § 119								
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No. 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 								
Attachment(s) 1) Notice of References Cited (PTO-892 2) Notice of Draftsperson's Patent Draw 3) Information Disclosure Statement(s) (Paper No(s)/Mail Date	ing Review (PTO-948)	4) 5) 6)	Interview Summary Paper No(s)/Mail Da Notice of Informal P Other:	ite				

Application/Control Number: 10/593,141 Page 2

Art Unit: 2812

DETAILED ACTION

This Office Action is in response to an Amendment filed 12/08/2008.

Currently, claims 16-29 are pending. Claims 1-15 have been cancelled.

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 16-21, 23, 24, 26 and 28 are rejected under 35 U.S.C. 102(b) as being anticipated by Johansson et al. (US 6,440,810 B1).

Regarding claim **16**, Johansson et al. discloses a method for the production of a bipolar transistor comprising a highly doped extrinsic base, wherein the method comprises the steps of: (col. 2, line 65-col. 3, line 10) providing a base layer(5) on a semiconductor substrate(1) (Fig. 2, col. 3, line 60); depositing a dielectric layer(7) in weakly doped or undoped fashion on the base layer (Fig. 3, col. 4, lines 11-16); applying an implantation mask (13) and patterning in such a way that an opening remains in a region provided for a later extrinsic base (Fig. 7, col. 4, lines 41-43); introducing BF₂ as a dopant of a first conductivity type into the dielectric layer after the application of the mask; indifusing, in a controlled thermal step, the dopant into the semiconductor substrate from the dielectric layer, an extrinsic base doped in low-resistance fashion arising (Fig. 5, col. 4, lines 25-34).

Regarding claim **17**, Johansson et al. discloses a method in which an oxide layer is deposited as the dielectric layer(5) (DS) (col. 4, lines 11-14).

Regarding claim **18**, Johansson et al. discloses a method in which an emitter window(15) is opened in the dielectric layer(5) (Fig. 7, col. 4, lines 41-43).

Regarding claim **19**, Johansson et al. discloses a method in which before the dopant is introduced into the dielectric layer, the emitter is produced by application and patterning of a polycrystalline emitter layer doped with a dopant of the second conductivity type above the emitter window (col. 5, lines 2-15).

Regarding claim **20**, Johansson et al. discloses a method in which the emitter layer is patterned by means of a photopatterned resist mask(13) that remains on the emitter and is later used as an implantation mask for the implantation of the dopant into the dielectric layer(5) (Fig. 8, col. 4, lines 41-59).

Regarding claim **21**, Johansson et al. discloses a method in which, for the production of the semiconductor substrate(1), in a semiconductor wafer doped with a dopant of the second conductivity type, active transistor regions are defined and are electrically insulated by oxide regions; and (Fig. 1, col. 3, lines 47-56) in which a base layer weakly doped with a dopant of the first conductivity type is grown epitaxially over the whole area (Fig. 2, col. 3, lines 60-66).

Regarding claim **23**, Johansson et al. discloses a method in which BF.sub.2 is implanted for the introduction of the dopant into the dielectric layer (Fig. 5, col. 4, lines 25-28).

Application/Control Number: 10/593,141 Page 4

Art Unit: 2812

Regarding claim **24**, Johansson et al. discloses a method in which BF_2 can be indiffused into the dielectric layer from the gas phase (Fig. 5, col. 4, lines 25-29).

Regarding claim **26**, Johansson et al. discloses a method in which the dielectric layer is removed after the patterning of the emitter layer and after the outdiffusion of the dopant in uncovered regions by etching (col. 5, lines 11-14).

Regarding claim **28**, Johansson et al. discloses a method in which a photomask(13) applied over an oxide layer over the emitter is used as the implantation mask, said photomask already having been used beforehand for the patterning of the emitter layer (Fig. 7, col. 4, lines 41-43).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:
 - 1. Determining the scope and contents of the prior art.
 - 2. Ascertaining the differences between the prior art and the claims at issue.
 - 3. Resolving the level of ordinary skill in the pertinent art.
 - 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

5. Claims 22, 25, 27 and 29 are rejected under 35 U.S.C. 103(a) as being unpatentable over Johansson et al. (US 6,40,810 B1) in view of Johnson (6,028,345).

Johansson et al. discloses the method substantially as claimed. See the preceding rejection of claims 16-21, 23, 24, 26 and 28 under 35 U.S.C. 102(b).

However, Johansson et al. fails to show that a buried collector layer is doped with a dopant of the second conductivity type, the doping of the emitter layer, and the production of metallic contacts.

Regarding claim **22**, Johnson discloses a method in which a buried collector layer(102) doped with a dopant of the second conductivity type is produced by implantation in the semiconductor wafer in the active transistor region(100), said collector layer serving for electrical connection of the collector (Fig. 3, col. 3, lines 40-46).

Regarding claim **25**, Johnson discloses a method in which the emitter layer is doped with arsenic, in which, during the indiffusion of the dopant into the base layer (BS)(110), arsenic also indiffuses into a surface region of the base layer (BS) from the emitter (E)(130) (Fig. 4, col. 3, line 63-col. 4, line 7).

Regarding claim **27**, Johansson et al. discloses a method further comprising the steps of: providing an n-doped semiconductor (Fig. 1, col. 3, lines 47-53); growing a p-doped base layer(5) epitaxially on the semiconductor wafer(1) over the whole area (Fig. 2, col. 3, lines 60-64); applying a dielectric layer(7) in weakly doped or undoped fashion on the base layer; opening an emitter window(15) in the dielectric layer (col. 4, lines 11-14); producing the emitter by application and patterning of an As-doped polycrystalline

emitter layer above the emitter window (Fig. 9, col. 4, lines 53-59, 64-65); introducing BF₂ as the dopant into the dielectric layer with the aid of an implantation mask (Fig. 5, col. 4, lines 25-28).

Johnson discloses method in which in a controlled thermal step, indiffusing boron from the dielectric layer into the base layer in the region of the extrinsic base, the latter acquiring low resistance, and simultaneously indiffusing arsenic into an upper region of the base layer from the emitter through the emitter window (Fig. 4, col. 3, line 47-col. 4, line 7).

Regarding claim **29**, Johnson et al. discloses a method in which the collector connection is effected via an n⁺-doped buried layer, and in which, over the emitter and in the region of the extrinsic base, the respective semiconductor is uncovered and metallic contacts(150) are produced above the latter (Fig. 8a-d, col. 4, lines 22-46). Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to combine the teachings of Johnson with the method of Johansson et al. to form a bipolar transistor that includes a collector region comprising a buried collector and doped epitaxial layer (col. 2, lines 53-61).

Response to Arguments

1. Applicant's arguments filed on 12/08/2008 have been fully considered but they are not persuasive. The examiner upon further inspection does not see a difference between what is claimed and the prior art, the opening disclosed in the prior art

reference and the claimed invention are in the same position, and undergo the same process of doping and diffusion. Further clarification is encouraged.

Conclusion

2. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Walter L. Lindsay, Jr. whose telephone number is (571) 272-1674. The examiner can normally be reached on Monday-Thursday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Charles Garber can be reached on (571) 272-2194. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/593,141 Page 8

Art Unit: 2812

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Walter L. Lindsay, Jr./
Primary Examiner, Art Unit 2812

3/15/2009